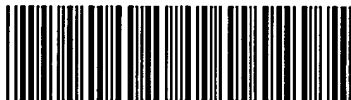


**Search Notes**

Application/Control No.

10/639,445

Examiner

Harold Kim

Applicant(s)/Patent under  
Reexamination

NAKAGAWA ET AL.

Art Unit

2182

**SEARCHED**

Class	Subclass	Date	Examiner
710	5, 2, 69	6/29/2005	HK
712	32, 35	6/26/2005	HK
711	147	6/29/2005	HK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	5	6/29/2005	HK
712	32, 35	6/29/2005	HK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, see attached search note	6/29/2005	HK
Inventor search on eDAN including USPAT# 6,353,863 and 6,643,713; consulted w/ Primary Christopher Shin, and SPE Dov Popovici	6/29/2005	HK